



MET Laboratories, Inc. *Safety Certification - EMI - Telecom Environmental Simulation*

914 WEST PATAPSCO AVENUE • BALTIMORE, MARYLAND 21230-3432 • PHONE (410) 354-3300 • FAX (410) 354-3313

33439 WESTERN AVENUE • UNION CITY, CALIFORNIA 94587 • PHONE (510) 489-6300 • FAX (510) 489-6372

3162 BELICK STREET • SANTA CLARA, CALIFORNIA 95054 • PHONE (408) 748-3585 • FAX (510) 489-6372

April 21, 2011

Ubiquiti Networks
91 E. Tasman
San Jose, CA 95134

Dear Robert Pera,

Enclosed is the EMC test report for compliance testing of the Ubiquiti Networks, NanoStationM5, tested to the requirements of ETSI EN 301 489-1 with ETSI EN 301 489-17 (Article 3.1(b) of R&TTE Directive).

Thank you for using the services of MET Laboratories, Inc. If you have any questions regarding these results or if MET can be of further service to you, please feel free to contact me.

Sincerely yours,
MET LABORATORIES, INC.

Jennifer Warnell
Documentation Department

Reference: (\ Ubiquiti Networks \ EMCS82947-ETS489)

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Electromagnetic Compatibility Test Report

For the

**Ubiquiti Networks
NanoStationM5**

Tested for Compliance with

ETSI EN 301 489-1

With ETSI EN 301 489-17 (Article 3.1(b) of R&TTE Directive)

MET Report: EMCS82947-ETS489

April 21, 2011

Prepared For:

**Ubiquiti Networks
91 E. Tasman
San Jose, CA 95134**

Prepared By:
MET Laboratories, Inc.
914 W. Patapsco Ave.
Baltimore, MD 21230

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MET Report: EMCS82947-ETS489



Lionel Gabrillo
Electromagnetic Compatibility Lab



Jennifer Warnell
Documentation Department

Engineering Statement: The measurements shown in this report were made in accordance with the procedures indicated, and the emissions from this equipment were found to be within the limits applicable. I assume full responsibility for the accuracy and completeness of these measurements, and for the qualifications of all persons taking them. It is further stated that upon the basis of the measurements made, the equipment tested is capable of operation in accordance with the requirements of ETSI EN 301 489-1 with ETSI EN 301 489-17 under normal use and maintenance.



Shawn McMillen,
Wireless Manager, Electromagnetic Compatibility Lab

Report Status Sheet

Revision	Report Date	Reason for Revision
Ø	April 21, 2011	Initial Issue.

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List of Terms and Abbreviations

AC	Alternating Current
ACF	Antenna Correction Factor
Cal	Calibration
<i>d</i>	Measurement Distance
dB	Decibels
dBμA	Decibels above one microamp
dBμV	Decibels above one microvolt
dBμA/m	Decibels above one microamp per meter
dBμV/m	Decibels above one microvolt per meter
DC	Direct Current
E	Electric Field
DSL	Digital Subscriber Line
ESD	Electrostatic Discharge
EUT	Equipment Under Test
<i>f</i>	Frequency
CISPR	Comite International Special des Perturbations Radioelectriques (International Special Committee on Radio Interference)
GRP	Ground Reference Plane
H	Magnetic Field
HCP	Horizontal Coupling Plane
Hz	Hertz
IEC	International Electrotechnical Commission
kHz	kiloHertz
kPa	kiloPascal
kV	kilovolt
LISN	Line Impedance Stabilization Network
MHz	MegaHertz
μH	microHenry
μF	microFarad
μs	microseconds
PRF	Pulse Repetition Frequency
RF	Radio Frequency
RMS	Root-Mean-Square
V/m	Volts per meter
VCP	Vertical Coupling Plane

1.0 Introduction

1.1 Overview

MET Laboratories, Inc. was contracted by Ubiquiti Networks to perform testing on the NanoStationM5, under Ubiquiti Networks purchase order number us100112.

This document describes the test setups, test methods, required test equipment, and the test limit criteria used to perform compliance testing of the NanoStationM5.

Model(s) Tested:	NanoStationM5
Model(s) Covered:	NanoStationM5
EUT Specifications:	Primary Power: 15V, 0.8A surge protection integrated PoE adapter
	Secondary Power: N/A
	Equipment Emissions Class: The radio equipment and/or associated ancillary equipment under test are classified as equipment for fixed use
Lab Ambient Test Conditions:	Temperature: 15-35° C
	Relative Humidity: 30-60%
	Atmospheric Pressure: 860-1060 mbar
Evaluated by:	Anderson Soungpanya
Report Date(s):	April 21, 2011

1.2 Test Site

All testing was performed at MET Laboratories, Inc., 3162 Belick St., Santa Clara, CA 95054. All equipment used in making physical determinations is accurate and bears recent traceability to the National Institute of Standards and Technology.

1.3 General Performance Criteria

The performance criteria cited in EN 301 489-17:

- performance criteria A for immunity tests with phenomena of a continuous nature;
- performance criteria B for immunity tests with phenomena of a transient nature;
- performance criteria C for immunity tests with power interruptions exceeding a certain time.

Note: For specific details on performance criteria, see sub-clause 6.2 of EN 301 489-17.

1.4 Testing Summary

Emissions

Descriptive Name	Requirement	Test Method	Result
Enclosure of Ancillary Equipment Measured on a Stand Alone Basis	ETSI EN 301 489-1, Section 8.2	EN 55016-2-3 (2006)	Not Applicable - EUT is not an Ancillary Equipment
DC Power Input/Output Ports	ETSI EN 301 489-1, Section 8.3	EN 55022 (2006)	Not Applicable – EUT is AC powered.
AC Mains Power Input/Output Ports	ETSI EN 301 489-1, Section 8.4	EN 55022 (2006)	Compliant
Harmonic Current Emissions (AC Mains Input Port)	ETSI EN 301 489-1, Section 8.5	EN 61000-3-2 +A1 (2006)	Compliant
Voltage Fluctuations and Flicker (AC Mains Input Port)	ETSI EN 301 489-1, Section 8.6	EN 61000-3-3 (1995)	Compliant
Telecommunication Ports	ETSI EN 301 489-1, Section 8.7	EN 55022 (2006)	Compliant

Immunity

Descriptive Name	Requirement	Test Method	Result
Radio Frequency Electromagnetic Field (80 MHz – 1000 MHz and 1400 MHz to 2700 MHz)	ETSI EN 301 489-1, Section 9.2	EN 61000-4-3 (2006)	Compliant
Electrostatic Discharge (ESD)	ETSI EN 301 489-1, Section 9.3	EN 61000-4-2 (2001)	Compliant
Fast Transient, Common Mode	ETSI EN 301 489-1, Section 9.4	EN 61000-4-4 (2004)	Compliant
Radio Frequency, Common Mode	ETSI EN 301 489-1, Section 9.5	EN 61000-4-6 (2005)	Compliant
Transient & Surges in the Vehicular Environment	ETSI EN 301 489-1, Section 9.6	ISO 7637-2 (2004) (12/24 VDC)	Not Applicable – Not meant to be used in a vehicle.
Voltage Dips and Interruptions	ETSI EN 301 489-1, Section 9.7	EN 61000-4-11 (2004)	Compliant
Surges	ETSI EN 301 489-1, Section 9.8	EN 61000-4-5 (2006)	Compliant

Table 1. Summary of Compliance Testing

1.5 Modifications to the Test Standard

No modifications were made to the test standard.

1.6 References

ETSI EN 301 489-1 V1.8.1 (2008-04)	Electromagnetic compatibility and Radio spectrum Matters (ERM); Electromagnetic Compatibility (EMC) standard for radio equipment and services; Part 1: Common technical requirements
ETSI EN301 489-17 V2.1.1(2009-05)	Electromagnetic compatibility and Radio spectrum Matters (ERM); Electromagnetic Compatibility (EMC) standard for radio equipment and services; Part 17: Specific conditions for Wideband data and HIPERLAN equipment
EN 55022	Information Technology Equipment – Radio Disturbance Characteristics – Limits and Methods of Measurement, 2006
EN 61000-3-3	Electromagnetic Compatibility (EMC) Part 3-3: Limits – Limitation of Voltage Changes, Voltage Fluctuations and Flicker in Public Low-Voltage Supply Systems, for Equipment with Rated Current ≤ 16 A per Phase and Not Subject to Conditional Connection, 1995
EN 61000-4-2	Electromagnetic Compatibility (EMC) Part 4-2: Testing and Measurement Techniques – Electrostatic Discharge Immunity Test, 2001
EN 61000-4-3	Electromagnetic compatibility (EMC) Part 4-3: Testing and Measurement Techniques – Radiated, Radio-Frequency, Electromagnetic Field Immunity Test, 2006
EN 55016-2-3	Specification for Radio Disturbance and Immunity Measuring Apparatus and Methods – Part 2-3: Methods of Measurement of Disturbances and Immunity – Radiated Disturbance Measurements, 2006
EN 61000-4-4	Electromagnetic Compatibility (EMC) Part 4-4: Testing and Measurement Techniques – Electrical Fast Transient/Burst Immunity Test, 2004
EN 61000-4-5	Electromagnetic Compatibility (EMC) Part 4-5: Testing and Measurement Techniques – Surge Immunity Test, 2006
EN 61000-4-6	Electromagnetic Compatibility - Part 4-6: Testing and Measurement Techniques Section – Immunity to Conducted Disturbances, Induced by Radio-Frequency Fields, 2005
EN 61000-4-11	Electromagnetic Compatibility - Part 4-11: Testing and Measurement Techniques – Voltage Dips, Short Interruptions and Voltage Variations Immunity Tests, 2004
ISO 7637-2	Road Vehicles – Electrical Disturbances from Conduction and Coupling – Part 2: Electrical Transient Conduction Along Supply Lines Only, 2004
EN 61000-3-2/Amendment 1	Electromagnetic Compatibility (EMC) – Part 3-2: Limits – Limits for Harmonic Current Emissions (Equipment Input Current Up to and Including 16 A per Phase, 2006

Table 2. Test References

2.0 Equipment Under Test

2.1 Description of Test Sample

The results obtained relate only to the item(s) tested.

The NanoStationM5, Equipment Under Test (EUT) for the remainder of this document, is a 5GHz Hi Power 2x2 MIMO AirMax TDMA Station.



Photograph 1. Ubiquiti Networks, NanoStationM5, Front View



Photograph 2. Ubiquiti Networks, NanoStationM5, Rear View

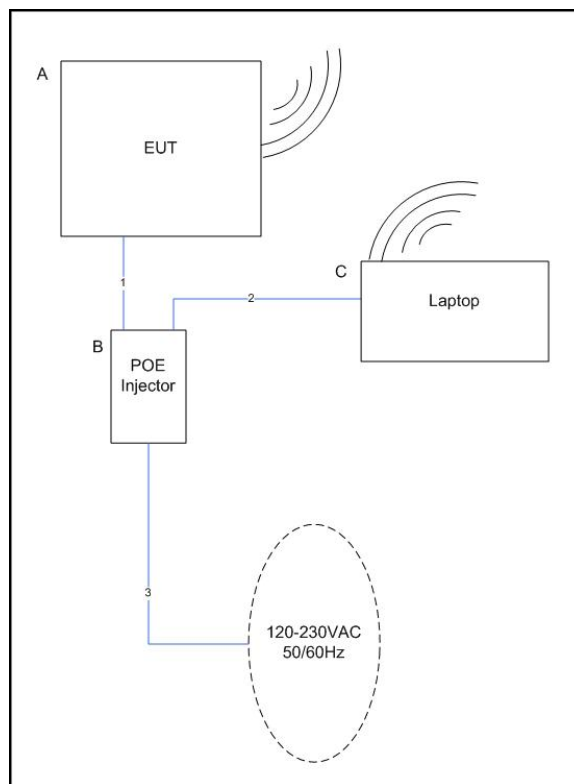


Figure 1. Block Diagram of Test Configuration

2.2 Equipment Configuration

The EUT was set up as outlined in Figure 1. All equipment incorporated as part of the EUT is included in the following list.

Ref. ID	Name / Description	Model Number	Serial Number
A	NanoStationM5	NS5	1040T00156D8A77BD
A	NanoStationM5	NS5	1103T002722101B00
A	NanoStationM5	NS5	1104T002722104F5D
B	Power Supply	UBI-POE-15-8	1101-0096733
B	Power Supply	UBI-POE-15-8	1101-0096734

Table 3. Equipment Configuration

2.3 Support Equipment

Support equipment necessary for the operation and testing of the EUT is included in the following list.

Ref. ID	Name / Description	Manufacturer	Model Number	Serial Number
C	Laptop	Dell	Vostro 1510	4953929473

Table 4. Support Equipment

2.4 Ports and Cabling Information

Ref. ID	Port Name on EUT	Cable Description	Qty.	Length (m)	Shielded (Y/N)	Termination Point
1	NanoM5 - Main	Ethernet	1	10	Y	PSU – POE port
	NanoM5- Secondary	Ethernet	1	10	Y	Unterminated
1	PSU - POE	Ethernet	1	10	Y	NanoM5 - Main
2	PSU - LAN	Ethernet	1	10	Y	Laptop
3	AC port	AC Cable	1	0.5	Y	100-240VAC Source

Table 5. Ports and Cabling Information

2.5 Mode of Operation

Transmit 6-54Mbps at 5GHz.

2.6 Method of Monitoring EUT Operation

IP connectivity is maintained with the EUT. If IP connectivity is lost, EUT connectivity shall be re-established upon power up or re-boot.

2.7 Modifications to the EUT

No modifications were made to the EUT.

2.8 Disposition of EUT

The test sample including all support equipment submitted to the Electro-Magnetic Compatibility Lab for testing was returned to Ubiquiti Networks upon completion of testing.

3.0 Electromagnetic Compatibility Emission Criteria

3.1 AC Mains Power Input/Output Ports: Limits for Conducted Emissions

Test Requirement(s): ETSI EN 301 489-1, Clause 8.4:

In accordance with *EN 55022 Clause 5.1*, the EUT shall meet the Class B limits shown in Table 6:

Limits for Conducted Emissions of Equipment				
Frequency Range (MHz)	intended for use in telecommunication centres only [EN 55022 Class A Limits] (dB μ V)		[EN 55022 Class B Limits] (dB μ V)	
	Quasi-Peak	Average	Quasi- Peak	Average
0.15 - 0.5	79	66	66 to 56	56 to 46
0.5 - 5	73	60	56	46
5 - 30	73	60	60	50

Table 6. Limits of Conducted Disturbance at AC Mains Power Input/Output Ports

Note: The lower limit shall apply at the transition frequencies. The limits decrease linearly with the logarithm of the frequency in the range of 0.15 MHz to 0.5 MHz.

Test Procedure:

The EUT was placed on a non-metallic table located in a shielded enclosure (See Photograph 3). The measurement was performed using normal operation of the equipment. The method of testing, test conditions, and test procedures of *Clause 9* of *EN 55022* were used. The EMC receiver scanned the frequency range from 150 kHz to 30 MHz. The measurements were performed over the frequency range of 0.15 MHz to 30 MHz using a 50 Ω / 50 μ H as the input transducer to an EMC field intensity meter. The tests were conducted in a RF-shielded enclosure.

Test Results:

The EUT was compliant with the specified requirements of Clause 8.4. Measured emissions were below applicable limits.

Test Engineer(s):

Jia Li

Test Date(s):

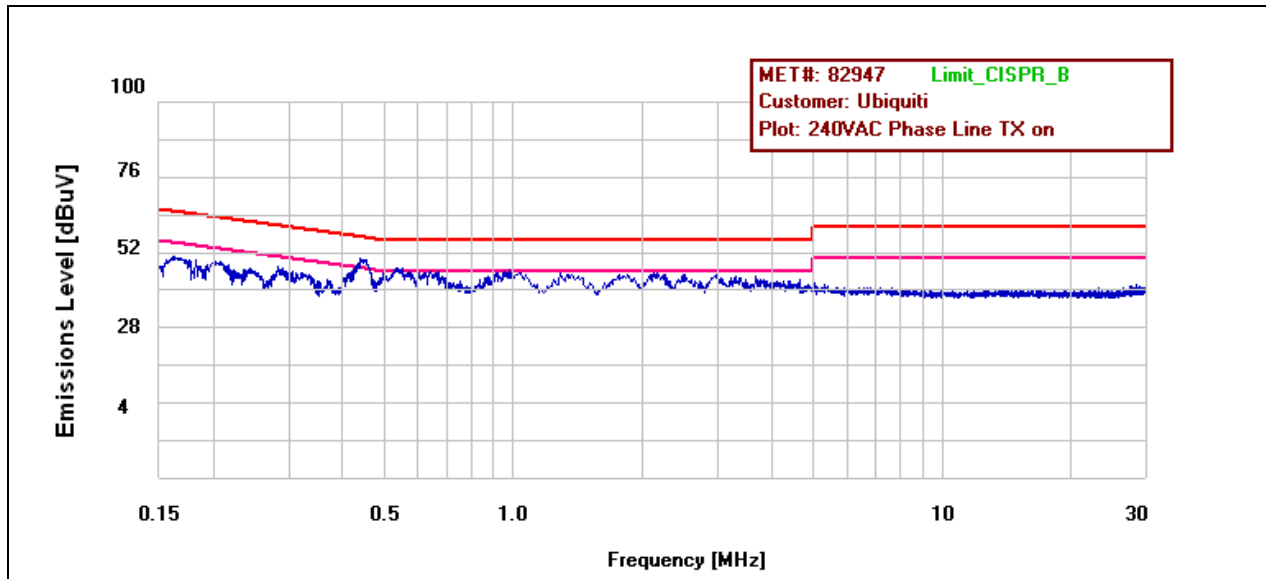
03/11/11

Electromagnetic Compatibility Emission

AC Mains Power Input/Output Ports: Limits for Conducted Emissions

Line	Freq. (MHz)	QP Amplitude	QP Limit	Delta	Pass	Average Amplitude	Average Limit	Delta	Pass
240VAC Phase TX on	0.452	44.15	56.862	-12.712	Pass	32.64	46.862	-14.222	Pass
240VAC Phase TX on	0.536	39.28	56	-16.72	Pass	27.325	46	-18.675	Pass
240VAC Phase TX on	2.88	35.68	56	-20.32	Pass	27.47	46	-18.53	Pass

Table 7. Conducted Emissions - Voltage, Worst Case Emissions, AC Power, Phase Line



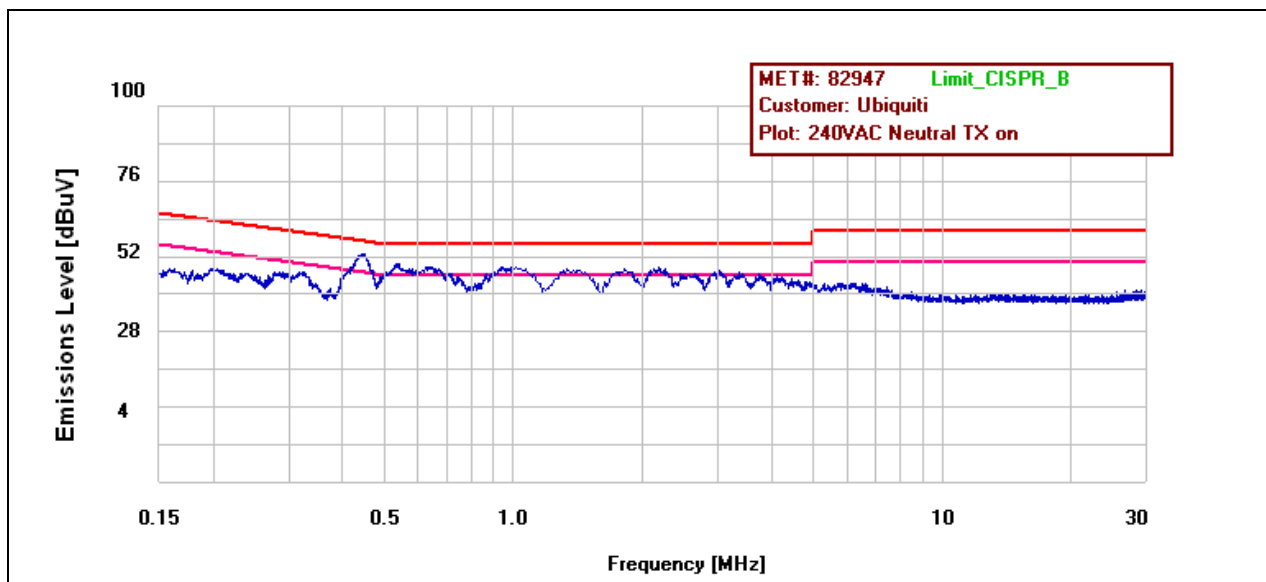
Plot 1. Conducted Emission Limits, Phase Line Plot

Electromagnetic Compatibility Emission

AC Mains Power Input/Output Ports: Limits for Conducted Emissions

Line	Freq. (MHz)	QP Amplitude	QP Limit	Delta	Pass	Average Amplitude	Average Limit	Delta	Pass
240VAC Neutral TX on	0.441	50.48	57.067	-6.587	Pass	43.87	47.067	-3.197	Pass
240VAC Neutral TX on	0.5288	45.48	56	-10.52	Pass	35.7	46	-10.3	Pass
240VAC Neutral TX on	0.9689	44.21	56	-11.79	Pass	35.81	46	-10.19	Pass

Table 8. Conducted Emissions - Voltage, Worst Case Emissions, AC Power, Neutral Line



Plot 2. Conducted Emission Limits, Neutral Line Plot

Electromagnetic Compatibility Emission

AC Mains Power Input/Output Ports: Limits for Conducted Emissions



Photograph 3. AC Mains Power Input/Output Ports, Conducted Disturbance, Test Setup

Electromagnetic Compatibility Emission

3.2 Harmonic Current Emissions

Test Requirement(s): ETSI EN 301 489-1, Clause 8.5:

Per *EN 61000-3-2+A1, Clause 7*, the EUT must not produce harmonic currents, which exceed the limits expressed in Table 9.

Harmonic Order	Maximum Permissible Harmonic Current (in Amperes)
Odd Harmonics	
3	2.30
5	1.14
7	0.77
9	0.40
11	0.33
13	0.21
$15 < n < 39$	$0.15 - 15/n$
Harmonic Order	Maximum Permissible Harmonic Current (in Amperes)
Even Harmonics	
2	1.08
4	0.43
6	0.30
$8 < n < 40$	$0.23 - 8/n$

Table 9. Harmonic Current Emission Limits from Section 7 of EN 61000-3-2

Test Procedure:

The EUT was placed on a non-metallic table (See Photograph 4). The measurement was performed using normal operation of the equipment. The method of testing, test conditions, and test procedures of *EN 61000-3-2+A1*.

Electromagnetic Compatibility Emission

Harmonic Current Emissions

Test Procedure (Con't): ITE is tested with the equipment configured to its rated current. In this case, the equipment, if necessary, may be configured with its power supplies loaded with additional load (resistive) boards to simulate rated current conditions. For ITE systems designed for use with a manufacturer-supplied power distribution system, e.g. transformers, UPS, power conditioner, etc., compliance with the limits of this standard shall be met at the input to the power distribution system.

Test Results: The EUT was compliant with the specified requirements of Clause 8.5. Measured emissions were below applicable limits.

Test Engineer(s): Jia Li

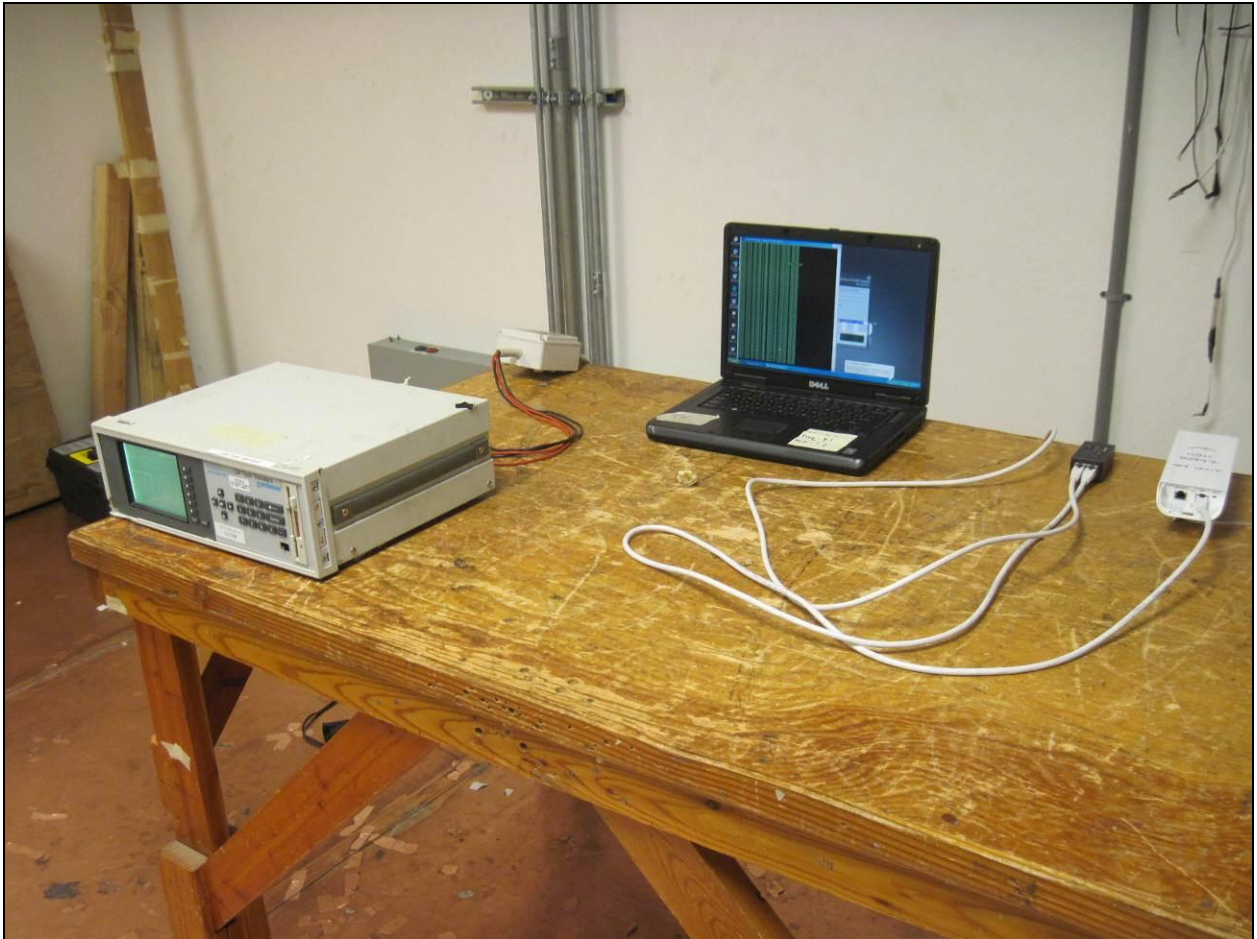
Test Date(s): 03/14/11

Class (A, B, C, D)	Voltage (V)	Current (A)	Frequency (Hz)	Total Harmonic Distortion (%)
A	243.35	40.69	49.997	232.86
Harmonic #	Measured (A)	Limit(A)✧	Results	Notes
3	0.01571	2.300	Pass	No Anomalies
5	0.01519	1.140	Pass	No Anomalies
7	0.01436	0.770	Pass	No Anomalies
9	0.01337	0.400	Pass	No Anomalies
11	0.01219	0.330	Pass	No Anomalies
13	0.01088	0.21	Pass	No Anomalies
15-39	0.0949-0.00107	0.150- 0.058	Pass	No Anomalies
2	0.00145	1.080	Pass	No Anomalies
4	0.00143	0.430	Pass	No Anomalies
6	0.00138	0.300	Pass	No Anomalies
8-40	0.00132-0.00041	0.230- 0.046	Pass	No Anomalies

Table 10. Harmonics, Test Results

Electromagnetic Compatibility Emission

Harmonic Current Emissions



Photograph 4. Harmonic Current Emissions, Test Setup

Electromagnetic Compatibility Emission

3.3 Voltage Fluctuations (Flicker)

Test Requirement(s): ETSI EN 301 489-1, Clause 8.6:

The EUT must not produce voltage fluctuations and/or flicker at the supply terminals as measured or calculated according to clause 4, according to limits expressed in *Clause 5*, under test conditions described in *Clause 6* and *Annex A* of *EN 61000-3-3*.

Test Procedure:

The EUT was placed on a non-metallic table (See Photograph 5). The EUT was operated with an AC main source at 220 V. Tests to prove the compliance of the EUT with the limits of *EN 61000-3-3, Section 5* were made using the test circuit provided in Figure 2 of *EN 61000-3-3*. The test circuit consisted of the test power supply, the reference impedance, the EUT, and a flickermeter. The test supply voltage (open-circuit voltage) was the rated voltage of the equipment. The test voltage was maintained within 2% of the nominal value. The frequency was 50 Hz \pm 0.5%. The total harmonic distortion of the supply voltage was less than 3%. The limits applicable to voltage fluctuations and flicker at the supply terminals of the EUT were automatically measured with the analyzer.

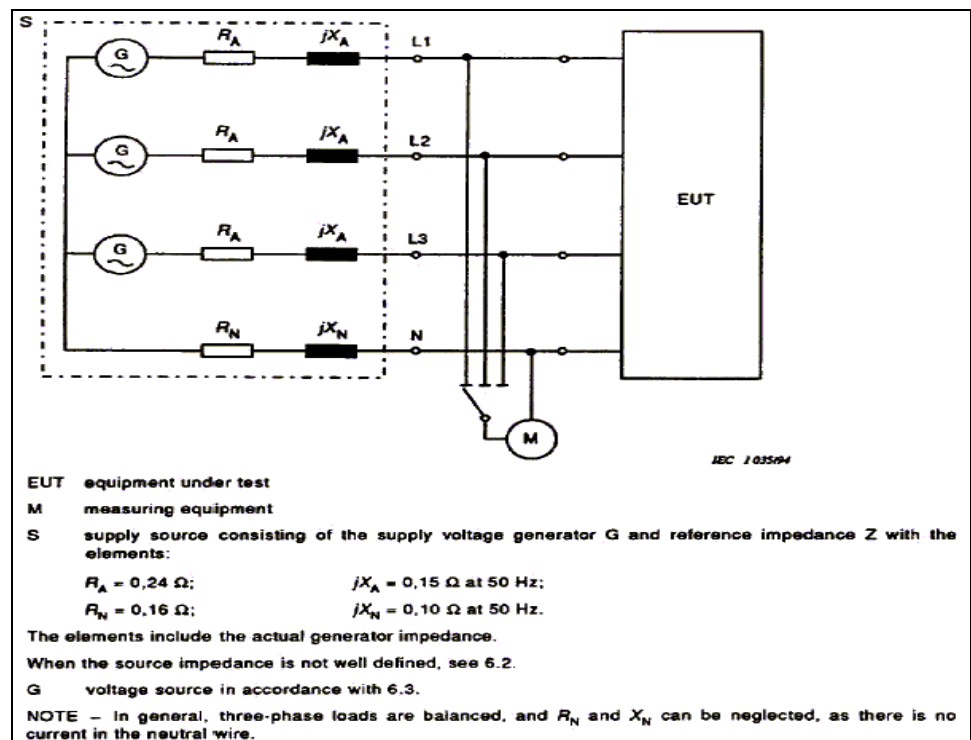


Figure 2. Test Circuit for EN 61000-3-3

Electromagnetic Compatibility Emission

Voltage Fluctuations (Flicker)

Test Results: The EUT was compliant with the specified requirements of Clause 8.6. Measured emissions were below applicable limits.

Test Engineer(s): Jia Li

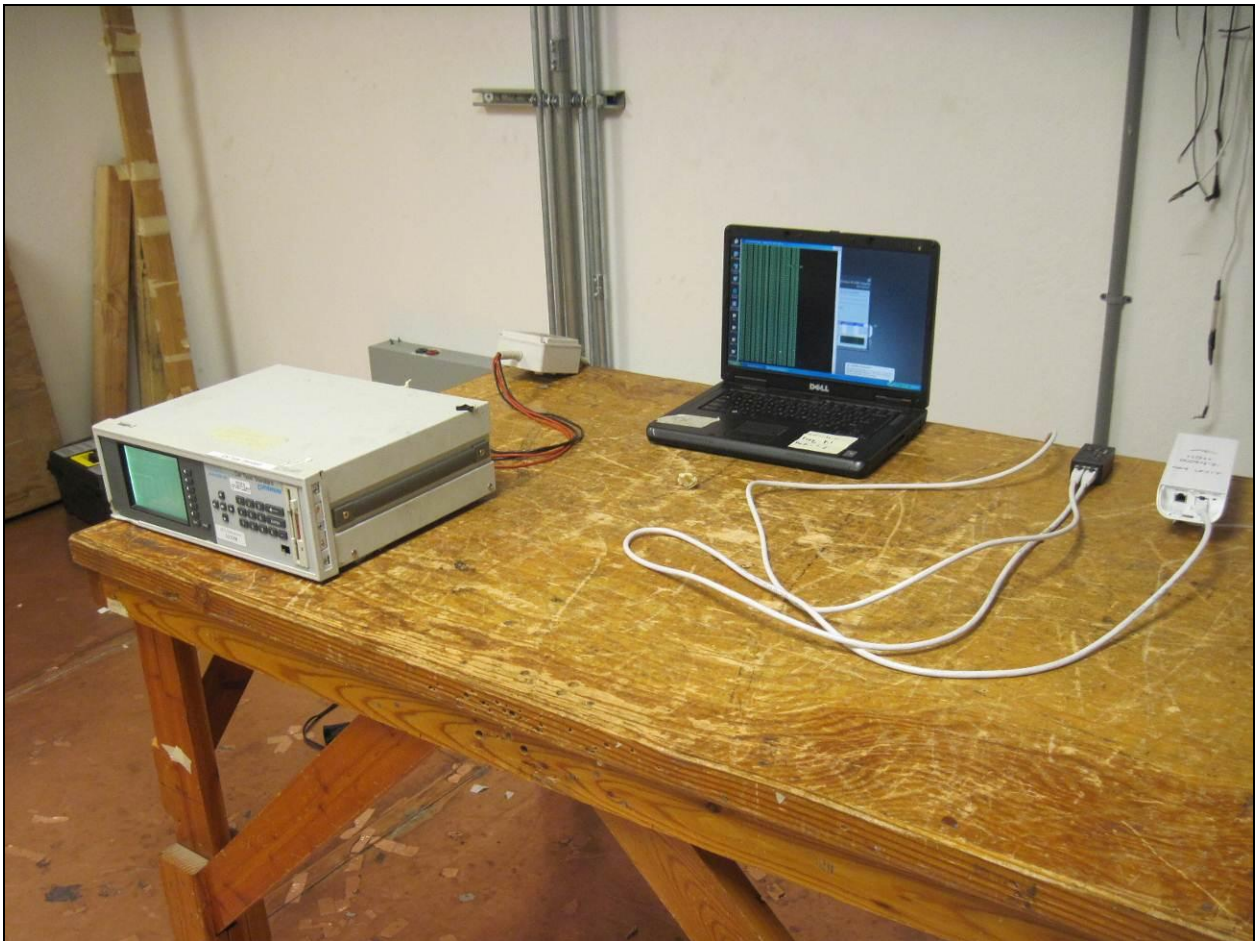
Test Date(s): 03/14/11

Voltage (V)	Current (A)	Frequency (Hz)	Power Factor	
243.3	41.05mA	50.003	0.389	
Average (Is) relative voltage Drop		d(t)	0.003%	
Relative voltage fluctuation (3s)		Dpp	0.001%	
d(t) at steady - state level		YES /NO	Yes	
Last relative steady - state level change		Dc	0.000%	
Last transition swing		Dmax	--	
Normalized peak flicker (3s)		Pp	0.00	
Parameter		Observation Period		Limit
		Short	Long	
Observation Time	Tp	10 min	120 min	
Maximum relative voltage change	dmax	0	0	4
Max rel. steady-state voltage change	dc	0	0	3
Duration of d(t) > 3 %	t	0	0	0.2
Short term flicker severity	Pst	0	0	1.0
Long term flicker severity	Plt	NA	0	0.65

Table 11. Flicker, Test Results

Electromagnetic Compatibility Emission

Voltage Fluctuations (Flicker)



Photograph 5. Voltage Fluctuations (Flicker), Test Setup

Electromagnetic Compatibility Emission

3.4 Telecommunications Ports

Test Requirement(s): ETSI EN 301 489-1, Clause 8.7:

The EUT must be in accordance with EN 55022 (2006), Section 5.2.

The EUT shall meet the Conducted Common Mode limits shown in Table 12:

Frequency Range (MHz)	Voltage Limits (dBμV)		Current Limits (dBμA)	
	Quasi-Peak	Average	Quasi- Peak	Average
0.15 - 0.5	84 to 74	74 to 64	40 to 30	30 to 20
0.5 - 30	74	64	30	20
Note: The limits decrease linearly with the logarithm of the frequency in the range of 0.15 MHz to 0.5 MHz. The current and voltage disturbance limits are derived for use with an ISN which presents a common mode (asymmetric mode) impedance of 150 Ω to the telecommunication port under test (conversion factor is $20 \log_{10} 150/1 = 44 \text{ dB}$).				

Table 12. Limits of Conducted Common Mode (Asymmetric Mode) Disturbance at Telecommunication Ports from Clause 5.2 of EN 55022 Class B

Test Procedure:

The EUT was placed on a non-metallic table located in a shielded enclosure (See Photograph 6). The measurements were performed using normal operation of the equipment. The method of testing, test conditions, and test procedures of *Clause 9* of *EN 55022* were used. The EMC receiver scanned the frequency range from 150 kHz to 30 MHz. The measurements were performed over the frequency range of 0.15 MHz to 30 MHz using an ISN, Current Probe or Capacitive Voltage Probe as the input transducer to an EMC field intensity meter.

Environmental Conditions for Conducted Emission	
Ambient Temperature:	22.4°C
Relative Humidity:	33%

Test Results:

The EUT was found compliant with the requirement(s) of this section.

Test Engineer(s):

Jia Li

Test Date(s):

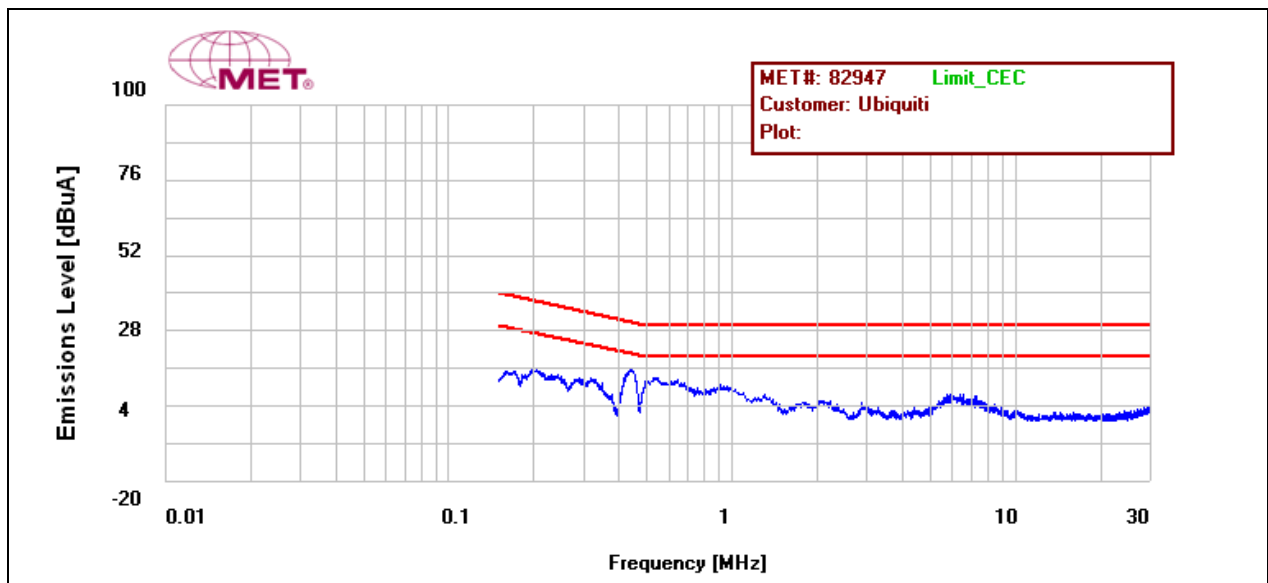
03/11/11

Limits for Conducted Disturbance at Telecommunication Ports

Conducted Emissions - Voltage for Telecommunication Ports, Worst Case Emissions, LAN Line

Line	Frequency (MHz)	Raw	QP Amplitude	QP Limit	Delta	Pass/Fail	Raw	Average Amplitude	Average Limit	Delta	Pass/Fail
LAN	0.444	31.9	9.9	30.987	-21.087	Pass	24.61	2.61	20.987	-18.377	Pass
LAN	0.2014	32.33	10.33	37.553	-27.223	Pass	28.79	6.79	27.553	-20.763	Pass
LAN	0.531	27.98	5.98	30	-24.02	Pass	17.87	-4.13	20	-24.13	Pass
LAN	1.01	24.1	2.1	30	-27.9	Pass	16.14	-5.86	20	-25.86	Pass
LAN	6.12	20.05	-1.95	30	-31.95	Pass	13.58	-8.42	20	-28.42	Pass
LAN	10.45	10.03	-11.97	30	-41.97	Pass	4.466	-17.534	20	-37.534	Pass

Table 13. Limits for Conducted Disturbance at Telecommunication Ports Test Results, LAN



Plot 3. Conducted Emission Limits for Telecommunications Ports, LAN Plot

Limits for Conducted Disturbance at Telecommunication Ports



Photograph 6. Limits for Conducted Disturbance at Telecommunication Ports

4.0 Electromagnetic Compatibility Immunity Criteria

4.1 Radio Frequency Electromagnetic Field

Test Requirement(s): ETSI EN 301 489-1, Clause 9.2:

Per EN 61000-4-3, the EUT must not be susceptible to a radiated electromagnetic field of 3 V/m, 80% amplitude modulated, in the frequency range 80 MHz to 1000 MHz and 1400 MHz to 2700 MHz (EN 61000-4-3). Performance criterion A applies.

The EUT was placed on a non-metallic table in the center of a 20' x 12' x 8' enclosure, and the radiating antenna was placed 3 m in front of the EUT (See Photograph 8). Support equipment for the EUT was located outside of the test room. The EUT was exposed to the required immunity fields. The amplitude and frequency of the radiated interference was set by an automated, computer-controlled system.

The chamber and signal generation/amplification system is calibrated to insure a uniform RF field with no EUT present. The recorded signal is played back by the controlling computer with the EUT placed in the area of uniform field. The signal source was stepped through the applicable frequency range at a rate no faster than 1% of the fundamental, as recommended in EN 61000-4-3. The signal was amplitude modulated 80% over the frequency range 80 MHz to 1000 MHz and 1400 MHz to 2700 MHz at a level of 3 V/m. Field presence was monitored during testing via a field probe placed in close proximity to the EUT. Throughout testing, the EUT was closely monitored for signs of susceptibility. The test was performed with the antennae oriented in both a horizontal and vertical polarization. Testing was performed in a semi-anechoic chamber.

Test Results: The EUT as tested was compliant with the requirements of Clause 9.2.

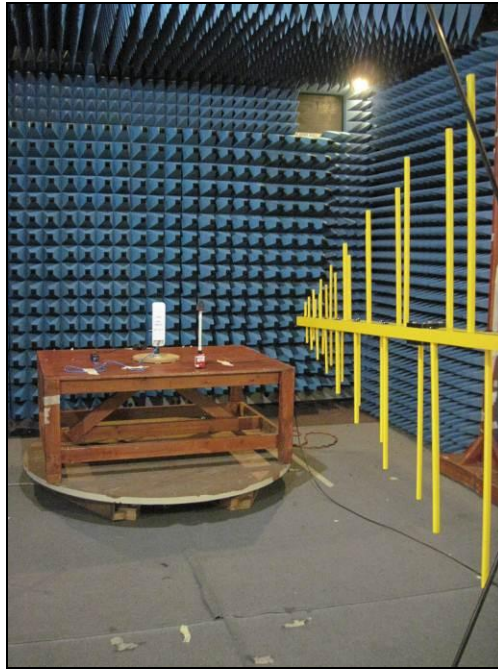
Test Engineer(s): Lionel Gabrillo

Test Date(s): 02/21/11

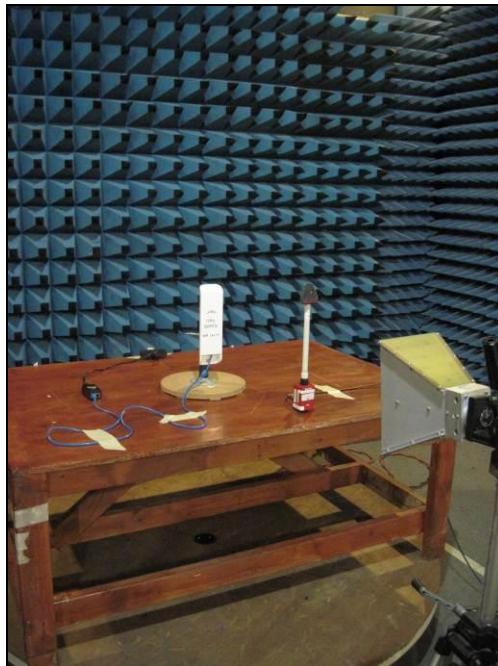
Start Frequency (MHz)	Stop Frequency (MHz)	Severity (V/m)	Polarity (H/V)	Modulation (Freq & Type)	Results			
					Front	Back	Left	Right
80	1000	3	V	1 kHz, 80%AM	Pass	Pass	Pass	Pass
80	1000	3	H	1 kHz, 80%AM	Pass	Pass	Pass	Pass
1400	2700	3	V	1 kHz, 80%AM	Pass	Pass	Pass	Pass
1400	2700	3	H	1 kHz, 80%AM	Pass	Pass	Pass	Pass

Table 14. Radiated Immunity, Test Results

Radio Frequency Electromagnetic Field



Photograph 7. Radio Frequency Electromagnetic Field, Test Setup, 80 MHz – 1 GHz



Photograph 8. Radio Frequency Electromagnetic Field, Test Setup, 1.4 GHz – 2.7 GHz

Electromagnetic Compatibility Immunity

4.2 Electrostatic Discharge

Test Requirement(s): ETSI EN 300 489-1 Clause 9.3:

Per *EN 61000-4-2*, the EUT was tested with air discharges of up to ± 8 kV, applied to non-conductive surfaces, and to contact discharges of up to ± 4 kV, applied to conductive surfaces of the EUT and the VCP. Performance Criterion A applies.

The EUT was placed on a non-metallic table located above a ground reference plane (GRP) (See Photograph 12), with a thickness of at least 0.25 mm, thus satisfying the requirements of *IEC 61000-4-2*:

It [the GRP] shall be a metallic sheet (copper or aluminum) of 0.25 mm minimum thickness.... The minimum size of the reference plane is 1 m², the exact size depending on the dimensions of the EUT. It shall project beyond the EUT or coupling plane by at least 0.5 m on all sides....

A horizontal coupling plane (HCP), 1.6 m x 0.8 m, shall be placed on the table. The EUT and cables shall be isolated from the coupling plane by an insulating support 0.5 mm thick.

A copper vertical coupling plane (VCP) measuring 0.5 m X 0.5 m was placed 0.1 m from the EUT. The VCP was connected to the GRP through two series 470 k Ω resistors. The GRP was connected to safety ground. The EUT was connected to the grounding system through its power cable only, in accordance with *EN 61000-4-2, Section 7.1, paragraph 4*:

The EUT shall be connected to the grounding system in accordance with its installation specifications. No additional grounding connections are allowed.

Ambient Temperature:	21°C
Relative Humidity:	28%
Atmospheric Pressure:	30 kPa

Environmental Conditions during EN 61000-4-2 Testing

Electromagnetic Compatibility Immunity

Electrostatic Discharge

Test Procedure: Air discharges of up to ± 8 kV were applied to non-conductive surfaces. Contact discharges of up to ± 4 kV were applied to conductive surfaces of the EUT. Contact discharges of ± 4 kV were applied to the HCP and VCP. Negative and positive discharges were applied at least ten times to each selected discharge point. The functionality of the EUT was determined during and after each discharge in accordance with Performance Criterion A.

Test Results: The EUT as tested was compliant with the requirements of Clause 9.3.

Test Engineer(s): Allen Gazza

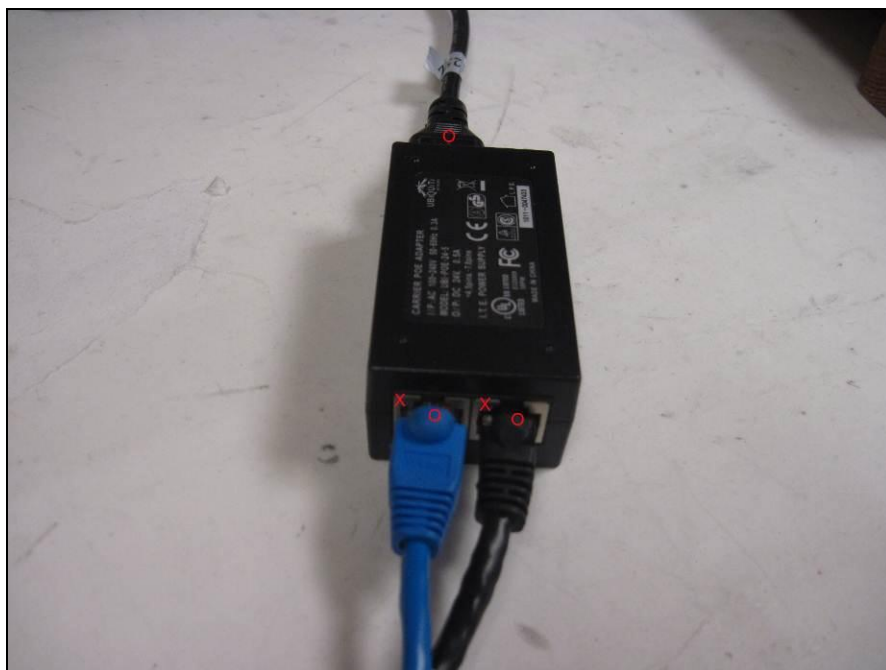
Test Date(s): 02/22/11

Discharge Type	Test Voltage (\pm kV)	Results				Anomalies
		Front	Back	Left	Right	
VCP	2	Pass	Pass	Pass	Pass	None
	4	Pass	Pass	Pass	Pass	None
HCP	2	Pass	Pass	Pass	Pass	None
	4	Pass	Pass	Pass	Pass	None
Contact Discharge	2	Pass	Pass	Pass	Pass	None
	4	Pass	Pass	Pass	Pass	None
Air Discharge	2	Pass	Pass	Pass	Pass	None
	4	Pass	Pass	Pass	Pass	None
	6	Pass	Pass	Pass	Pass	None
	8	Pass	Pass	Pass	Pass	None

Table 15. Electrostatic Discharge, Test Results



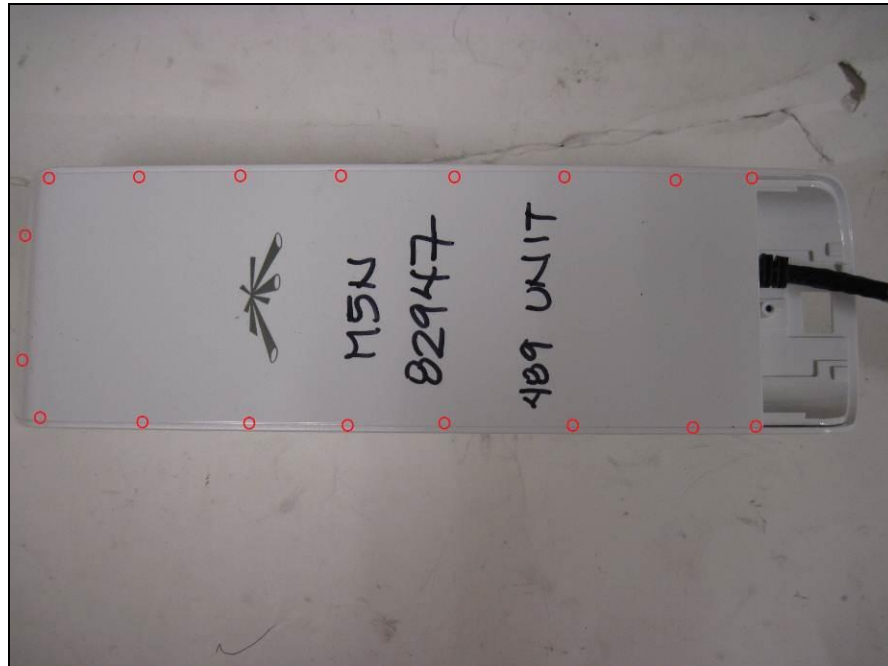
Photograph 9. Electrostatic Discharge, Test Points, Bottom



Photograph 10. Electrostatic Discharge, Test Points, PSU Top

X = Contact Discharge Test Points

O = Air Discharge Test Points

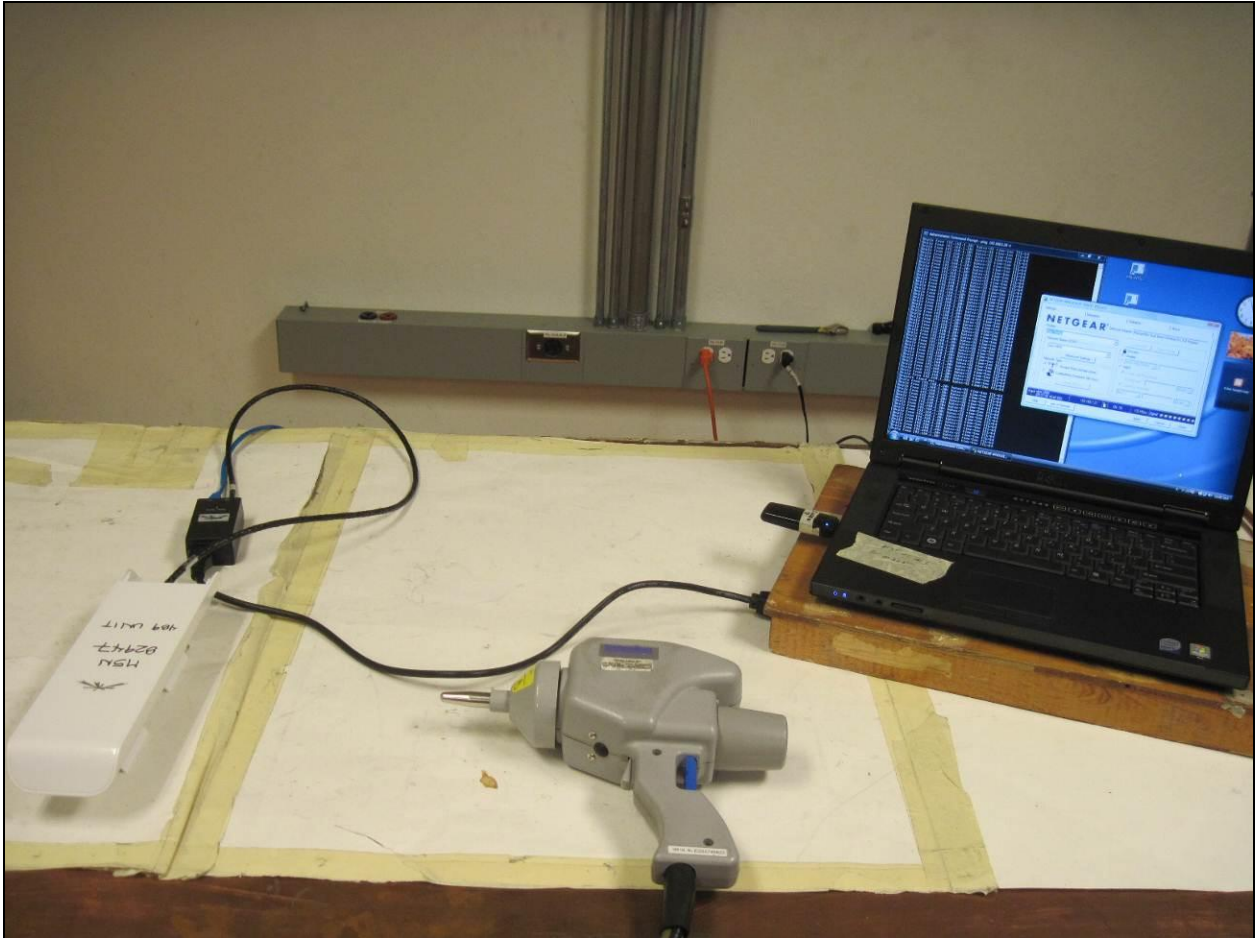


Photograph 11. Electrostatic Discharge, Test Points, Top

X = Contact Discharge Test Points
O = Air Discharge Test Points

Electromagnetic Compatibility Immunity

Electrostatic Discharge



Photograph 12. Electrostatic Discharge, Test Setup

Electromagnetic Compatibility Immunity

4.3 Fast Transient, Common Mode

Test Requirement(s): ETSI EN 300 489-1, Clause 9.4:

Per *EN 61000-4-4*, The EUT was tested with the electrical fast transients shown in Figure 3, having an amplitude of ± 1 kV applied to the AC power cables (plug type); ± 0.5 kV applied to the DC power cables; ± 0.5 kV applied to I/O and data lines. Only cables that could potentially exceed 3 m in length in real-world application of the EUT need be tested. Performance criterion A applies for all tests.

Test Procedure:

The EUT was placed on a 0.1m non-metallic support above a GRP (See Photograph 13). The Electrical Fast Transient/Burst (EFT/B) generator and the coupling clamp were mounted to the ground plane. For application of the fast transients to the power lines, power was supplied to the EUT through the EFT/B generator. For application of the fast transients to I/O, data and control lines, the cables were individually placed in the coupling clamp, which was also connected to the EFT/B generator.

The EFT/B generator was operated to couple the required transient bursts to each line of the power input in common mode. Transient bursts were applied for a period not less than one minute with both positive transients and negative transients.

The EUT was then powered from an isolated circuit, and selected I/O, data and control cables were placed one at a time in the capacitive coupling clamp. The EFT/B generator was operated to inject the required bursts onto each selected cable via the coupling clamp.

Throughout testing, the EUT was monitored closely for signs of susceptibility.

Electromagnetic Compatibility Immunity

Fast Transient, Common Mode

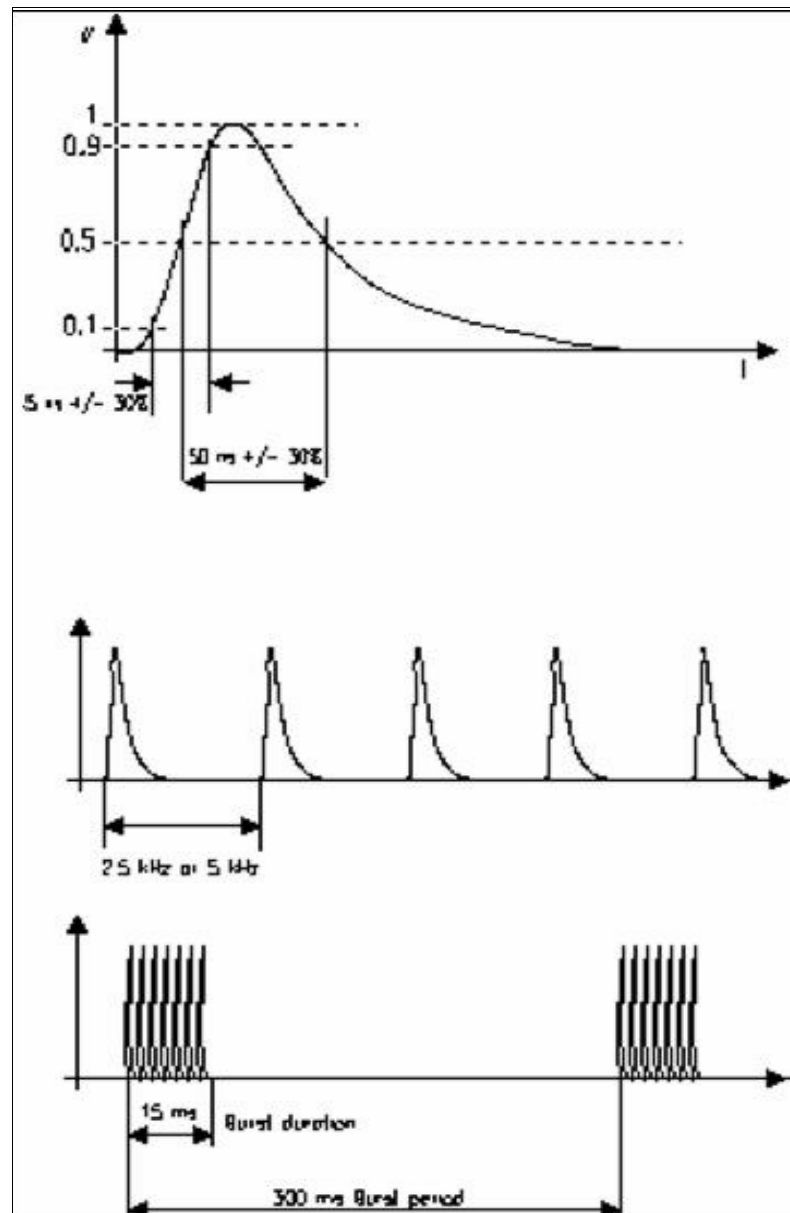


Figure 3. EN 61000-4-4 Test Waveform

Electromagnetic Compatibility Immunity

Fast Transient, Common Mode

Test Results: The EUT as tested was found compliant with the requirements of Clause 9.4.

Test Engineer(s): Jia Li

Test Date(s): 03/14/11

Port Name	Slot/EUT Side	Test Level	PASS	Anomalies
AC Power				
AC Adaptor	NA	±1 kV	Yes	No Anomalies

Port Name	Slot/EUT Side	Test Level	PASS	Anomalies
I/O Cables				
LAN	Rear	±0.5 kV	Yes	No Anomalies

Table 16. Fast Transient, Test Results

Fast Transient, Common Mode



Photograph 13. Fast Transient, Common Mode, Test Setup, AC Setup



Photograph 14. Fast Transient, Common Mode, Test Setup, I/O Setup

Electromagnetic Compatibility Immunity

4.4 Radio Frequency, Common Mode

Test Requirement(s): ETSI EN 300 489-1, Clause 9.5:

Per *EN 61000-4-6*, all interconnecting cables on the EUT including AC power lines, data and control lines shall be tested for immunity to conducted radio frequencies in the range 0.15 MHz - 80 MHz. Using the bulk current injection method, I/O and data cables must be tested to a level of 3 Vrms. The injection voltage shall be amplitude modulated at 80% by a 1 kHz tone. Performance Criterion A applies for all tests.

Test Procedure:

The EUT was placed on a 0.1m non-metallic support above a GRP (See Photograph 15). For power line cables, a Coupling Decoupling Network (CDN) was used. The CDN was initially calibrated in a calibration jig with a 50 Ω RF load and a 100 Ω matching resistor on one side, and a 100 Ω matching resistor and the receiver (spectrum analyzer) on the other. The injection voltage level was adjusted to maintain a monitored voltage of 3 Vrms across the frequency range (0.15 MHz to 80 MHz).

For cables other than the power line in the frequency range 0.15 MHz - 80 MHz, the BCI was initially calibrated in a calibration jig with a 50 Ω RF load and a 100 Ω matching resistor on one side, and a 100 Ω matching resistor and the receiver (spectrum analyzer) on the other. The injection voltage level was adjusted to maintain a monitored voltage of 3 Vrms across the frequency range (0.15 MHz to 80 MHz). The BCI was clamped around the cable under test at a distance of 0.1 to 0.3 m from the EUT.

Electromagnetic Compatibility Immunity

Radio Frequency, Common Mode

Test Results: The EUT as tested was found compliant with the requirements of Clause 9.5.

Test Engineer(s): Joe Vang

Test Date(s): 03/14/11

Slot/EUT Side	Port Name	Results / Anomalies
bottom	AC	Pass; No Anomalies Observed
bottom	LAN	Pass; No Anomalies Observed

Table 17. Conducted Immunity, Test Results

Radio Frequency, Common Mode



Photograph 15. Radio Frequency, Common Mode, Test Setup, AC Setup



Photograph 16. Radio Frequency, Common Mode, Test Setup,, I/O Setup

Electromagnetic Compatibility Immunity

4.5 Voltage Dips and Short Interruptions

Test Requirement(s): ETSI EN 300 489-1, Clause 9.7:

Per EN 61000-4-11, the EUT shall be tested for the following voltage dips, interruptions and variations:

5.2.4.4 Voltage Dips and Short Interruptions		
Unit	Test level and Characteristic	Performance Criterion
Voltage reduction % Duration ms	>95 10	B
Voltage reduction % Duration ms	>95 20	B
Voltage reduction % Duration ms	30 500	C
Voltage reduction % Duration ms	>95 5000	C

Table 18. Voltage Dips and Short Interruptions Limits

Test Procedure: The EUT was placed on a non-metallic table and situated in the center of a GRP. The EUT was provided with AC power via the programmable power supply (See Photograph 17). The power supply was programmed to perform the applicable set of voltage dips, interruptions and variations. Each sequence was repeated three times to verify the results.

Results: The EUT as tested was found compliant with the requirements of Clause 9.7.

Test Engineer: Jia Li

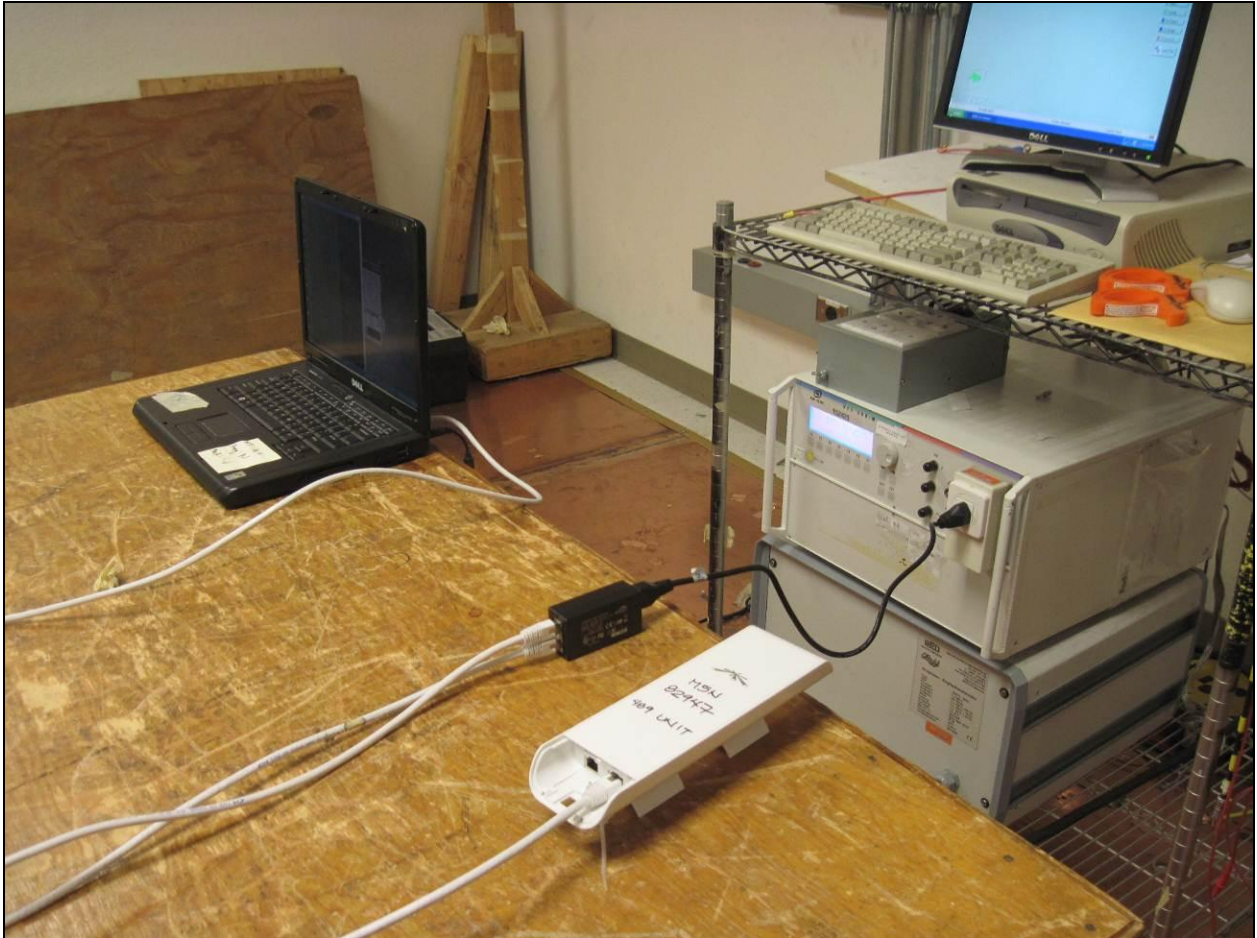
Test Date: 03/14/11

Test Type	Parameters	No of Rep.	Criterion Required	Criterion Achieved	Results	Anomalies
Voltage Dips	0% drop for 10 ms or 1/2 cycle	3	B	A	Pass	No Anomalies
Voltage Dips	0% drop for 20 ms or 1 cycle	3	B	A	Pass	No Anomalies
Voltage Dips	70% drop for 500 ms or 25 cycles	3	C	A	Pass	No Anomalies
Short Interrupts	0% drop for 5000 ms or 250 cycles	3	C	C	Pass	EUT turns off, but recovers with human intervention. Criterion C achieved.

Table 19. Voltage Dips and Interruptions, Test Results

Electromagnetic Compatibility Immunity

Voltage Dips and Short Interruptions



Photograph 17. Voltage Dips and Interruptions, Test Setup

Electromagnetic Compatibility Immunity

4.6 Surges

Test Requirement(s): ETSI EN 301 489-1, Clause 9.8:

The EUT was tested with the surge waveforms shown on the following page, having an open circuit amplitude of ± 1 kV applied to the I/O interconnection cables. Performance criterion A applies for I/O cables.

The EUT was tested with the surge waveforms shown on the following page, having an open circuit amplitude of ± 1 kV (differential mode), and ± 2 kV (common mode) applied to the AC power cables. Performance Criterion A applies for AC power cables.

Test Procedure:

The EUT was placed on a non-metallic table above a GRP extending at least 1 m beyond all sides of the EUT (See Photograph 18). For I/O port surges, For application of the fast transients to I/O, data and control lines, the cables were individually placed in the coupling clamp, which was also connected to the EFT/B generator. These three tests were performed with positive surges and negative surges. For other I/O interconnection lines, a coupling de-coupling network [CDN] is required in order to avoid possible adverse effects on equipment not under test and to provide sufficient decoupling impedance to the surge wave so that the specified wave may be developed on the lines under test. The length of the interconnection line between the CDN and the EUT shall be 2 m or shorter.

AC power [where applicable] was supplied to the EUT through the Combination Wave Generator. The combination wave generator was configured to produce the following output:

Open Circuit Voltage:	Front Time = 1.2 μ s Time to Half = 50 μ s
Short Circuit Current:	Front Time = 8 μ s Time to Half = 20 μ s
Telecom wave parameters:	Front Time = 10 μ s Time to Half = 700 μ s

Table 20. Combination Wave Generator Test Parameters for EN 61000-4-5

Electromagnetic Compatibility Immunity

Surges

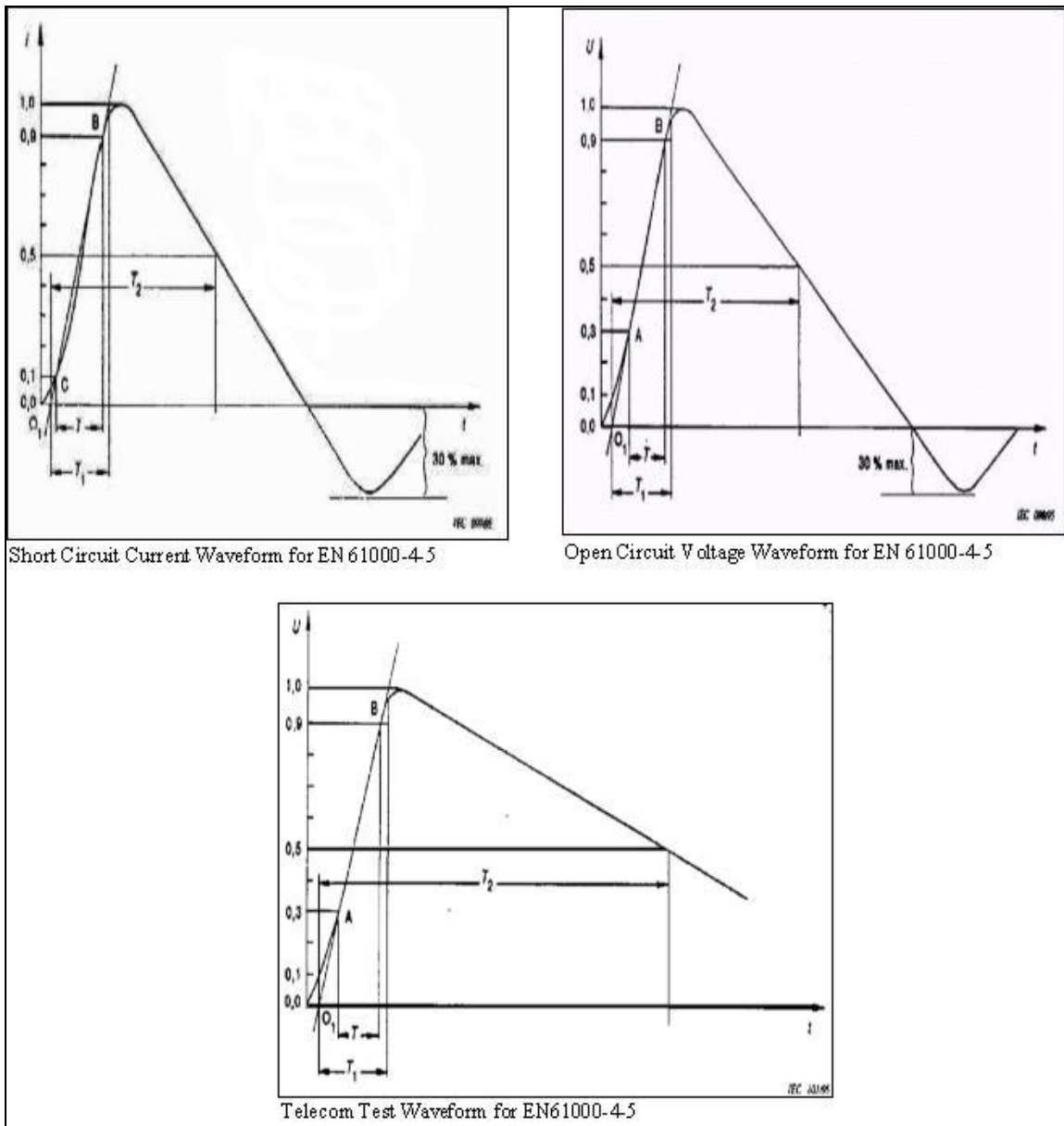


Figure 4. EN 61000-4-5 Surge Test Waveforms

Electromagnetic Compatibility Immunity

Surges

Test Procedure (Continued):

For AC power lines, the Combination Wave Generator was operated to couple the required surges between each EUT input power phase and ground, and from line to line. These three tests were performed with positive surges and negative surges, synchronized with the power input phase at 0°, 90°, and 270°. Throughout testing, the EUT was monitored closely for signs of susceptibility. For I/O port surges, surge waveforms were applied via a CDN, in accordance with *Section 7 of EN 61000-4-5*.

Test Results: The EUT as tested was found compliant with the requirements of Clause 9.8.

Test Engineer(s): Joe Vang

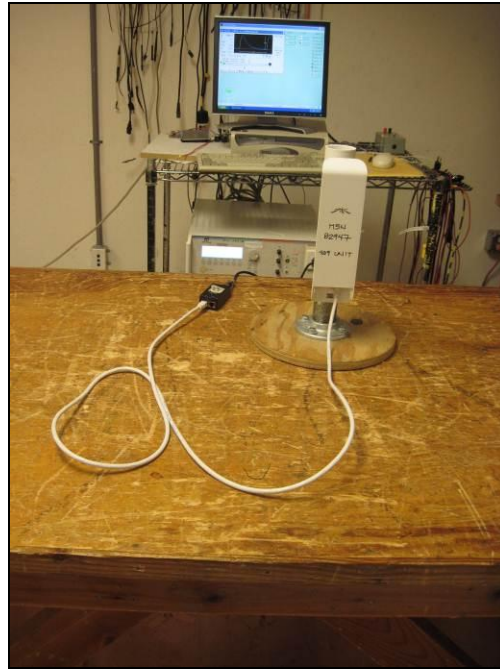
Test Date(s): 03/16/11

Port Name	Coupling	Phase	Test Level	Results	Anomalies
AC, Differential Mode					
Phase to Neutral	Phase to Neutral	0	±1.0 kV	Pass	No Anomalies
		90	±1.0 kV	Pass	No Anomalies
		180	±1.0 kV	Pass	No Anomalies
		270	±1.0 kV	Pass	No Anomalies
AC, Common Mode					
Phase to Ground	Phase to Ground	0	±2.0 kV	Pass	No Anomalies
		90	±2.0 kV	Pass	No Anomalies
		180	±2.0 kV	Pass	No Anomalies
		270	±2.0 kV	Pass	No Anomalies
Neutral to Ground	Neutral to Ground	0	±2.0 kV	Pass	No Anomalies
		90	±2.0 kV	Pass	No Anomalies
		180	±2.0 kV	Pass	No Anomalies
		270	±2.0 kV	Pass	No Anomalies

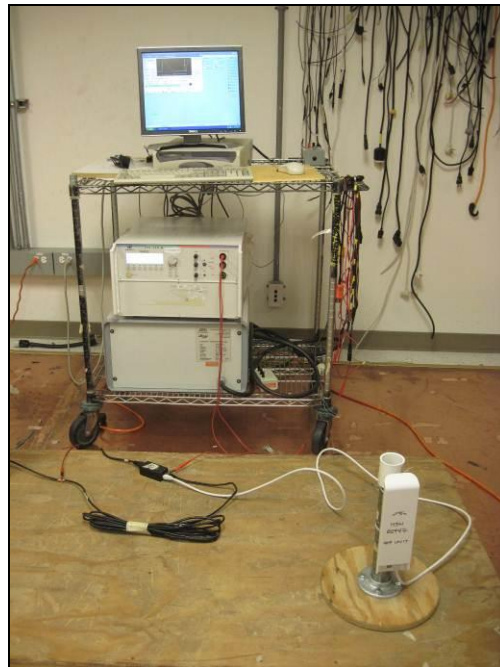
Port Name	Phase	Test Level	Results	Anomalies
I/O Cables				
LAN Port	Phase to Neutral	±1 kV	Pass	No Anomalies

Table 21. Surges, Test Results

Surges



Photograph 18. Surges, Test Setup, AC Setup



Photograph 19. Surges, Test Setup, I/O Setup



5.0 Test Equipment

Calibrated test equipment utilized during testing was maintained in a current state of calibration per the requirements of ANSI/NCSS Z540-1-1994 and ANSI/ISO/IEC 17025:2000.

Test Name: AC Conducted Emissions Voltage Clause 8.4			Test Date(s): 03/11/11		
MET Asset #	Nomenclature	Manufacturer	Model	Last Cal Date	Cal Due Date
1S2657	SCREEN ROOM	ETS LINDGREN	14W-2/2-0	SEE NOTE	
1S2407	SPECTRUM ANALYZER ESA-E	AGILENT/HP	E4407B	7/30/2010	7/30/2011
1S2633	TRANSIENT LIMITER	FISCHER CUSTOM COMMUNICATIONS INC.	FCC-450B-2.4-N	SEE NOTE	
1S2678	LISN, DUAL-LINE V- NETWORK	TESEQ	NNB 51	12/1/2010	12/1/2011
Test Name: Harmonic Current Emissions Clause 8.5			Test Date(s): 03/14/11		
MET Asset #	Nomenclature	Manufacturer	Model	Last Cal Date	Cal Due Date
1S2398	POWER MEASUREMENT UNIT	COMBINOVA	A300	3/31/2010	3/31/2011
1S2496	GROUND PLANE 4	MET LABS	N/A	N/A	N/A
Test Name: Voltage Fluctuations (Flicker) Clause 8.6			Test Date(s): 03/14/11		
MET Asset #	Nomenclature	Manufacturer	Model	Last Cal Date	Cal Due Date
1S2398	POWER MEASUREMENT UNIT	COMBINOVA	A300	3/31/2010	3/31/2011
1S2496	GROUND PLANE 4	MET LABS	N/A	N/A	N/A
Test Name: Telecom Line Conducted Emissions Clause 8.7			Test Date(s): 03/11/11		
MET Asset #	Nomenclature	Manufacturer	Model	Last Cal Date	Cal Due Date
1S2657	SCREEN ROOM	ETS LINDGREN	14W-2/2-0	SEE NOTE	
1S2407	SPECTRUM ANALYZER ESA-E	AGILENT/HP	E4407B	7/30/2010	7/30/2011
1S2633	TRANSIENT LIMITER	FISCHER CUSTOM COMMUNICATIONS INC.	FCC-450B-2.4-N	SEE NOTE	
1S2678	LISN, DUAL-LINE V- NETWORK	TESEQ	NNB 51	12/1/2010	12/1/2011
1U0148	RF CURRENT PROBE	SOLAR ELECTRONICS	9207-1	8/16/2010	8/16/2011
1S2653	2653	AMPLIFIER	SONOMA INSTRUMENT	SEE NOTE	
Test Name: Radiated Electromagnetic Field Clause 9.2			Test Date(s): 02/21/11		
MET Asset #	Equipment	Manufacturer	Model	Last Cal Date	Cal Due Date
1S2264	3 METER CHAMBER	LINDGREN	N/A	7/29/2010	7/29/2011
1S2401	BILOG ANTENNA	SCHAFFNER	CBL6140A	SEE NOTE	
1S2208	HORN ANTENNA	EMCO	3115	SEE NOTE	
1S2643	SIGNAL GENERATOR 40GHZ	ANRITSU	MG3694B	2/11/11	2/11/12
1S2576	AMPLIFIER (80- 1000MHZ)	AMPLIFIER RESEARCH	500W1000A	SEE NOTE	
1U0257	AMPLIFIER	AMPLIFIER RESEARCH	25S1G4A	SEE NOTE	
1S2579	ISOTROPIC ELECTRIC FIELD PROBE	ETS-LINDGREN	HI-6053	11/10/10	11/10/11



Ubiquiti Networks
NanoStationM5

Test Equipment
ETSI EN 301 489-1 with ETSI EN 301 489-17

Test Name: Electrostatic Discharge Immunity Clause 9.3				Test Date(s): 02/22/11	
MET Asset #	Equipment	Manufacturer	Model	Last Cal Date	Cal Due Date
1S2470	ESD DISCHARGE MODULE	NOISEKEN	ESS-2000	04-26-2010	04-26-2011
1S2491	GROUND PLANE	N/A	GROUND PLANE #3	N/A	N/A
Test Name: Fast Transients Clause 9.4				Test Date(s): 03/14/11	
MET Asset #	Equipment	Manufacturer	Model	Last Cal Date	Cal Due Date
1S2104	CLAMP, COUPLING, CAPACITIVE	HEAFELY	N/A	SEE NOTE	
1S2423	ULTRA COMPACT SIMULATOR	AMPLIFIER RESEARCH	UCS-500M-6A	SEE NOTE	
1S2496	GROUND PLANE 4	MET LABS	N/A	N/A	N/A
Test Name: Radio Frequency, Conducted Continuous Clause 9.5				Test Date(s): 03/14/11	
MET Asset #	Equipment	Manufacturer	Model	Last Cal Date	Cal Due Date
1S2621	CI FIXTURE	MET LABS	N/A	11/22/2010	11/22/2011
1S2569	SPECTRUM ANALYZER	AGILENT	E4401B	SEE NOTE	
1S2578	AMPLIFIER (10K-250MHZ)	AMPLIFIER RESEARCH	75A250A	SEE NOTE	
1S2512	TRANSIENT LIMITER	AGILENT	11947A	SEE NOTE	
1S2409	SYNTHESIZED RF SIGNAL GENERATOR	GIGATRONICS	6062A	11/30/2010	11/30/2011
1S2624	COUPLING/DECOUPLING NETWORK	COM-POWER	CDN-M325	SEE NOTE	
1S2657	SCREEN ROOM	ETS LINDGREN	14W-2/2-0	SEE NOTE	
1S2096	EM INJECTION CLAMP	FCC	F2031	SEE NOTE	
Test Name: Voltage Dips and Short Interruptions Clause 9.7				Test Date(s): 03/14/11	
MET Asset #	Equipment	Manufacturer	Model	Last Cal Date	Cal Due Date
1S2423	ULTRA COMPACT SIMULATOR	AMPLIFIER RESEARCH	UCS-500M-6A	SEE NOTE	
1S2496	GROUND PLANE 4	MET LABS	N/A	N/A	N/A
Test Name: Surges Clause 9.8				Test Date(s): 03/16/11	
MET Asset #	Equipment	Manufacturer	Model	Last Cal Date	Cal Due Date
1S2423	ULTRA COMPACT SIMULATOR	EM TEST	UCS-500M-6A	SEE NOTE	
1S2491	GROUND PLANE	MET LABS	GROUND PLANE #3	N/A	N/A

Note: Functionally verified test equipment is verified using calibrated instrumentation at the time of testing.